



Power MOSFETS

DATASHEET

LM1A027NHX8A

N-Channel
Enhancement Mode MOSFET

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Quality Management Systems
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description

TOLL Top View	Bottom View	Symbol	Product Summary		
			Symbol	N-Channel	Unit
			V _{DSS}	100	V
			R _{DSON-Max}	2.5	mΩ
			I _D	245	A

Feature

- High Speed Power Switching
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

Applications

- Synchronous Rectification in SMPS
- Hard Switching and High Speed Circuit
- Industrial Motor Drive

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1A027NHX8A	TOLL	Tape & Reel	2000 / Tape & Reel	1A027 □□□□□□

Note : □□□□□□ = Lot Code

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V _{DSS}	Drain-Source Voltage	100	V
V _{GSS}	Gate-Source Voltage	±20	
T _J	Maximum Junction Temperature	175	°C
T _{STG}	Storage Temperature Range	-55 to 175	°C
I _S	Diode Continuous Forward Current	T _c =25°C 68	A
I _{DM}	Pulse Drain Current Tested	T _c =25°C 626	A
I _D ⁽¹⁾	Continuous Drain Current	T _c =25°C 245 T _c =100°C 177	A
P _D	Maximum Power Dissipation	T _c =25°C 250 T _c =100°C 125	W
I _D	Continuous Drain Current	T _A =25°C 29 T _A =70°C 24	A
P _D	Maximum Power Dissipation	T _A =25°C 3.3 T _A =70°C 2.3	W
I _{AS} ⁽²⁾	Avalanche Current, Single pulse	L=0.1mH 75 L=0.5mH 41	A
E _{AS} ⁽²⁾	Avalanche Energy, Single pulse	L=0.1mH 282 L=0.5mH 421	mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit
R _{θJC}	Thermal Resistance-Junction to Case	Steady State	0.6 °C/W
R _{θJA} ⁽³⁾	Thermal Resistance-Junction to Ambient	Steady State	45 °C/W

Note ① : Max. current is limited by max. junction temperature.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150 °C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

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N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{DS}}=250\mu\text{A}$	100	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=80\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{DS}}=250\mu\text{A}$	2	3	4	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$R_{\text{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}$, $I_{\text{DS}}=20\text{A}$	-	2	2.5	$\text{m}\Omega$
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_{\text{DS}}=10\text{A}$	-	37.6	-	S
Dynamic Characteristics ^⑤						
R_{G}	Gate Resistance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=0\text{V}$, Freq.=1MHz	-	0.3	-	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=50\text{V}$, Freq.=1MHz	-	8532	-	pF
C_{oss}	Output Capacitance		-	2380	-	
C_{rss}	Reverse Transfer Capacitance		-	72	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{GS}}=10\text{V}$, $V_{\text{DS}}=25\text{V}$, $I_{\text{D}}=1\text{A}$, $R_{\text{GEN}}=1\Omega$	-	25.7	-	nS
t_{r}	Turn-on Rise Time		-	12.7	-	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	69.8	-	
t_{f}	Turn-off Fall Time		-	131.1	-	
Q_{g}	Total Gate Charge	$V_{\text{GS}}=6\text{V}$, $V_{\text{DS}}=50\text{V}$, $I_{\text{D}}=20\text{A}$	-	97	-	nC
Q_{g}	Total Gate Charge	$V_{\text{GS}}=10\text{V}$, $V_{\text{DS}}=50\text{V}$, $I_{\text{D}}=20\text{A}$	-	147.4	-	
Q_{gs}	Gate-Source Charge		-	42.2	-	
Q_{gd}	Gate-Drain Charge		-	39.2	-	
Source-Drain Characteristics						
$V_{\text{SD}}^{\circledast}$	Diode Forward Voltage	$I_{\text{SD}}=10\text{A}$, $V_{\text{GS}}=0\text{V}$	-	0.75	1.1	V
t_{rr}	Reverse Recovery Time	$I_{\text{F}}=10\text{A}$, $V_{\text{R}}=50\text{V}$	-	80.8	-	nS
Q_{rr}	Reverse Recovery Charge	$dI_{\text{F}}/dt=100\text{A}/\mu\text{s}$	-	160.3	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

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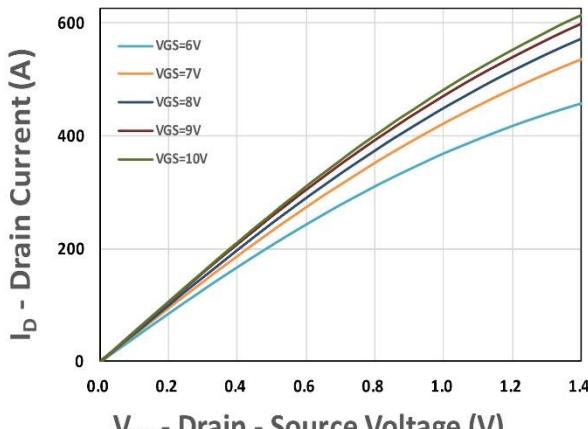


Figure 1. Output Characteristics

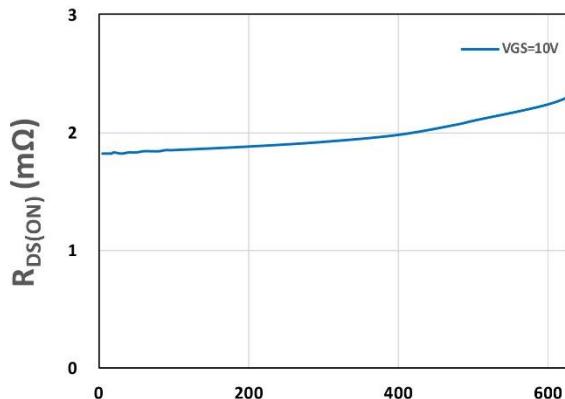


Figure 2. On-Resistance vs. ID

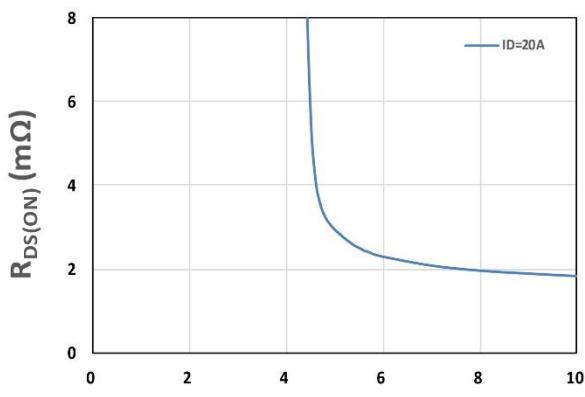


Figure 3. On-Resistance vs. VGS

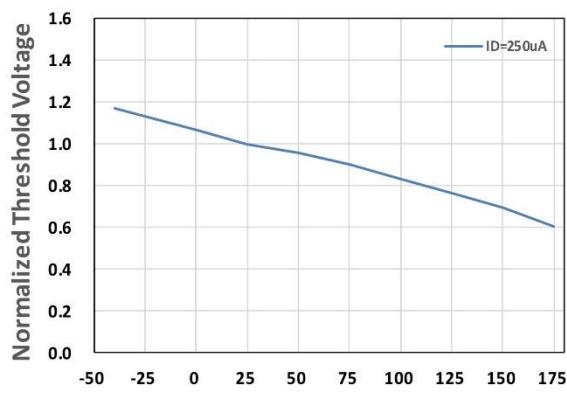


Figure 4. Gate Threshold Voltage

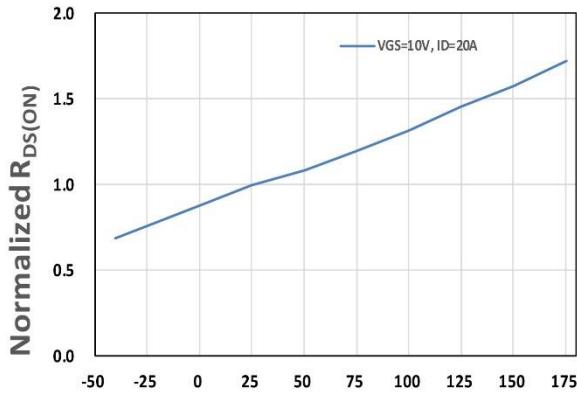


Figure 5. Drain-Source On Resistance

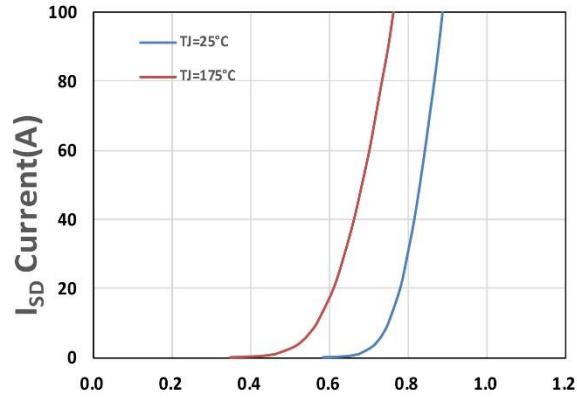
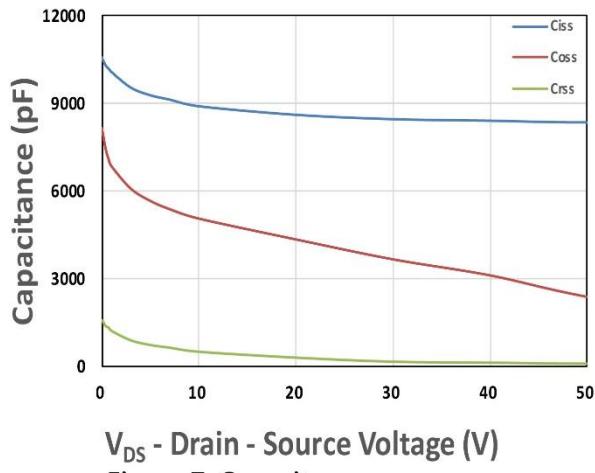


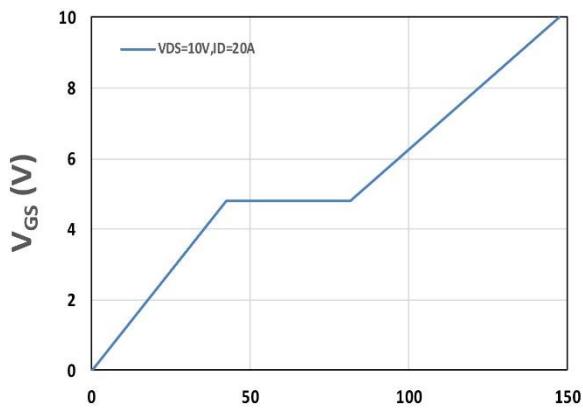
Figure 6. Source-Drain Diode Forward

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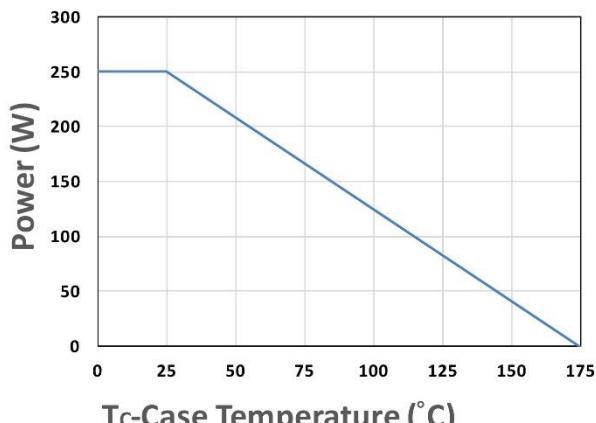
V_{DS} - Drain - Source Voltage (V)

Figure 7. Capacitance



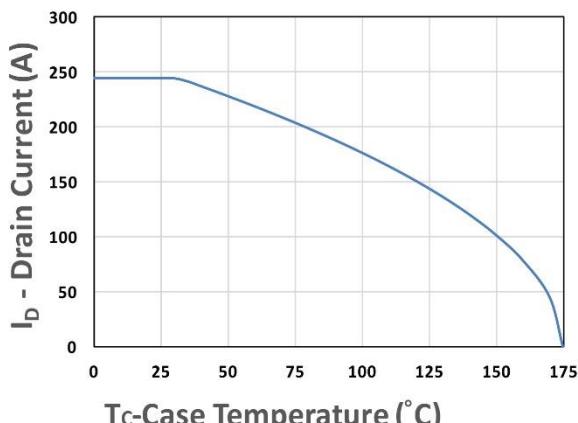
V_{GS} (V)

Figure 8. Gate Charge Characteristics



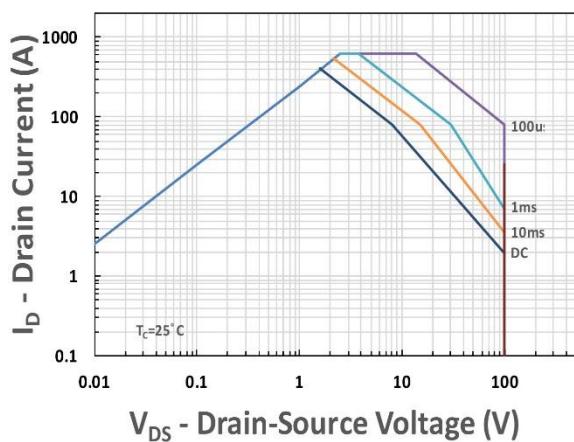
T_c-Case Temperature (°C)

Figure 9. Power Dissipation



I_D - Drain Current (A)

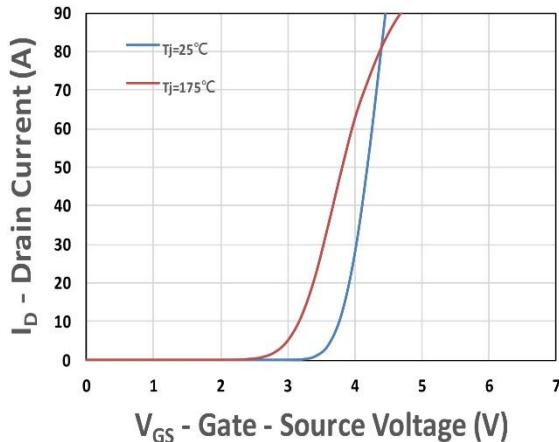
Figure 10. Drain Current



I_D - Drain Current (A)

V_{DS} - Drain-Source Voltage (V)

Figure 11. Safe Operating Area



I_D - Drain Current (A)

V_{GS} - Gate - Source Voltage (V)

Figure 12. Transfer Characteristics

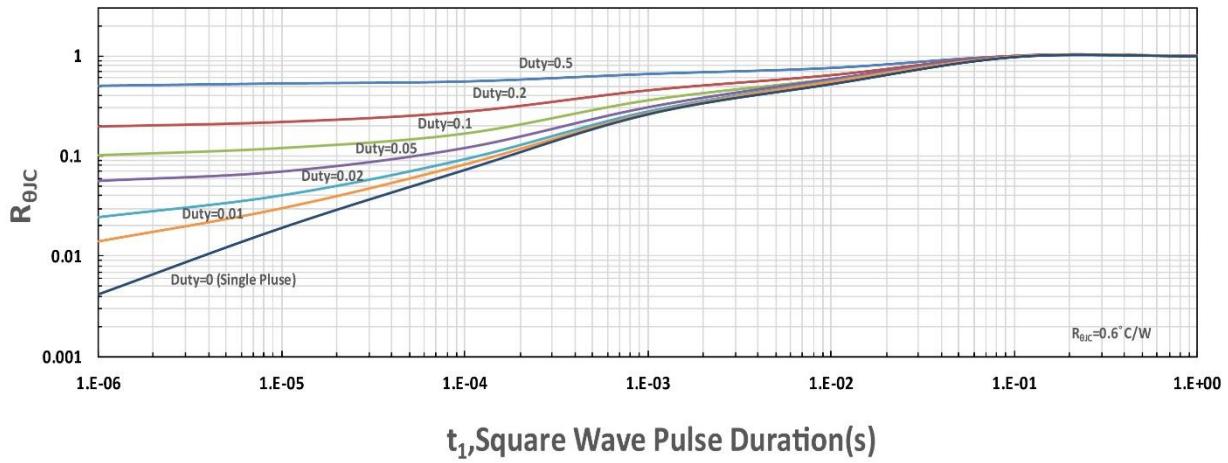


Figure 13. $R_{\theta JC}$ Transient Thermal Impedance